

<b>Notice of References Cited</b>	Application/Control No. 10/777,142		Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner Leith A. Al-Nazer		Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,002,812	02-2006	Sakaki, Yoichiro	361/803
	B	US-			
	C	US-			
	D	US-			
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**NON-PATENT DOCUMENTS**

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